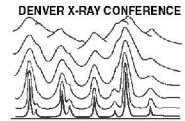


Advances in X-ray Analysis
Volumes 1- 39 (1957 – 1995)



**Volume 35A. First Pacific-International
Congress on X-ray Analytical Methods
(PICXAM). Fortieth Annual Conference on
Applications of X-ray Analysis, August 7-16,
1991**

[Table of
Contents](#)

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CONTENTS

PART A

I. WHOLE PATTERN FITTING, RIETVELD ANALYSIS
AND CALCULATED DIFFRACTION PATTERNS

PARTICLE STATISTICS AND WHOLE-PATTERN METHODS IN QUANTITATIVE X-RAY POWDER DIFFRACTION ANALYSIS	1
D. K. Smith	
CALCULATED PATTERNS IN X-RAY POWDER DIFFRACTION ANALYSIS	17
G. J. McCarthy, K. J. Martin, J. M. Holzer, D. G. Grier, W. M. Syvinski and D. W. Nodland	
APPLICATIONS OF RIETVELD ANALYSIS TO MATERIALS CHARACTERIZATION IN SOLID-STATE CHEMISTRY, PHYSICS AND MINERALOGY	25
R. J. Hill	
VARIABLE STEP-COUNTING TIMES FOR RIETVELD ANALYSIS, OR, GETTING THE MOST OUT OF YOUR EXPERIMENT TIME	39
I. C. Madsen and R. J. Hill	
NEW FEATURES AND ADVANCED APPLICATIONS OF SIROQUANT: A PERSONAL COMPUTER XRD FULL PROFILE QUANTITATIVE ANALYSIS SOFTWARE PACKAGE	49
J. C. Taylor and R. A. Clapp	
EFFECT OF POWDER SAMPLE GRANULARITY ON FLUORESCENT INTENSITY AND ON THERMAL PARAMETERS IN X-RAY DIFFRACTION RIETVELD ANALYSIS	57
C. J. Sparks, R. Kumar, E. D. Specht, P. Zschack, G. E. Ice, T. Shiraishi and K. Hisatsune	
RIETVELD ANALYSIS AND PAIR WISE SUBSTITUTIONAL ALLOYS	63
W. D. Kaplan and G. Kimmel	
SIZE-STRAIN AND QUANTITATIVE PHASE ANALYSIS BY THE RIETVELT METHOD	69
P. Scardi, L. Lutterotti and R. Di Maggio	
ELECTRON DENSITY DISTRIBUTION OBTAINED FROM X-RAY POWDER DATA BY THE MAXIMUM ENTROPY METHOD	77
M. Sakata, M. Takata, Y. Kubota, T. Uno, S. Kumazawa and C. J. Howard	
HIGH RESOLUTION X-RAY POWDER DIFFRACTION BY THE COMBINATION OF SYNCHROTRON RADIATION AND IMAGING PLATE TO OBSERVE ELECTRON DISTRIBUTION BY THE MAXIMUM ENTROPY METHOD	85
M. Takata, M. Yamada, Y. Kubota and M. Sakata	

II. QUANTITATIVE PHASE ANALYSIS BY X-RAY DIFFRACTION (XRD)

THE EFFECTS OF SAMPLING ERROR ON DETECTION LIMITS DETERMINED FOR QUANTITATIVE X-RAY DIFFRACTION	91
G. A. Raab and P. Dalheim	
A MULTI-LINE STANDARDLESS METHOD FOR X-RAY POWDER DIFFRACTION PHASE ANALYSIS	105
D. Y. Li and B. H. O'Connor	
AUTOMATED QUANTITATIVE XRF ANALYSIS SOFTWARE IN QUALITY CONTROL APPLICATIONS	111
A. J. Klimasara	
QUANTITATIVE XRD ANALYSIS BY PARTIAL LEAST SQUARES - APPLICATION IN A COMMERCIAL PRODUCT	117
A. G. Mateos	

III. THIN-FILM AND SURFACE CHARACTERIZATION BY XRD

X-RAY REFLECTION, A NEW TOOL FOR INVESTIGATING LAYERED STRUCTURES AND INTERFACES	127
B. Lengeler	
CHARACTERIZATION OF SINGLE- AND MULTIPLE-LAYER FILMS BY X-RAY REFLECTOMETRY	137
T. C. Huang and W. Parrish	
GRAZING-INCIDENCE X-RAY ANALYSIS OF SURFACES AND THIN FILMS	143
T. C. Huang	
DETERMINATION OF CRYSTAL STRUCTURE AND CATION DISTRIBUTION IN THIN FILMS	151
G. Will, T. C. Huang and F. Sequeda	
CHARACTERIZATION OF PZT THIN FILMS - CRYSTALLOGRAPHIC PHASES	159
R. P. Goehner, M. O. Eatough, B. A. Tuttle and T. J. Headley	
DEPTH PROFILING OF CERAMIC SPECIMENS USING MULTI-WAVELENGTH X-RAY BRAGG-BRENTANO DIFFRACTION DATA WITH PARTICULAR REFERENCE TO ZIRCONIA-ALUMINAS	169
A. van Riessen and B. H. O'Connor	
PREDICTION OF THE DIFFRACTION ORDER DEPENDENCE OF THE INTEGRAL REFLECTION COEFFICIENT OF MULTILAYER STRUCTURES USING ATOMIC FORCE MICROSCOPE MEASUREMENTS	177
D. B. Brown, J. H. Konnert, J. V. Gilfrich, P. D'Antonio, R. K. Freitag, H. B. Rosenstock and P. G. Burkhalter	
A SIMPLE SETUP FOR GLANCING ANGLE POWDER DIFFRACTION WITH A SEALED X-RAY TUBE	185
P. Georgopoulos, J. R. Levine, Y. W. Chung and J. B. Cohen	
X-RAY DIFFRACTION STUDIES ON LAMINATED MAGNETIC RECORDING MEDIA	191
G. L. Gorman, T. Yogi, S. E. Lambert and D. P. Alvarez	

SYNTHESIS ANALYSIS OF THIN FILMS BY XRD AND SEM	197
G. Fujinawa and S. Tobe	
CHARACTERIZATION OF EPITAXIAL HIGH T_c SUPERCONDUCTORS USING A PARALLEL BEAM X-RAY DIFFRACTOMETER	205
E. Houtman, T. W. Ryan, B. David and V. Doormann	
POWDER X-RAY DIFFRACTION CHARACTERIZATION OF LASER DEPOSITED FERROELECTRIC THIN FILMS	211
W. Wong-ng, T. C. Huang, L. P. Cook, P. K. Schenck, M. D. Vaudin, C. K. Chiang, L. H. Robins and P. S. Brody	
IV. LATTICE DEFECTS AND X-RAY TOPOGRAPHY	
CHARACTERIZATION OF LATTICE DEFECTS AND CONCOMITANT STRAIN DISTRIBUTION	221
S. Weissmann	
APPLICATION OF SYNCHROTRON AND FLASH X-RAY TOPOGRAPHY TO IMPROVED PROCESSING OF ELECTRONIC MATERIALS	239
J. M. Winter, Jr., R. E. Green, Jr., and K. A. Green	
INVESTIGATION OF SEMICONDUCTOR HETEROSTRUCTURES BY WHITE BEAM SYNCHROTRON X-RAY TOPOGRAPHY IN GRAZING BRAGG-LAUE AND CONVENTIONAL BRAGG GEOMETRIES	247
G.-D. Yao, J. Wu, T. Fanning and M. Dudley	
CHARACTERIZATION OF PEROVSKITE-LIKE SUBSTRATES FOR THIN FILM SUPERCONDUCTORS USING SYNCHROTRON X-RAY TOPOGRAPHY	255
G.-D. Yao, S. Y. Hou, M. Dudley and J. M. Phillips	
V. TEXTURE ANALYSIS BY XRD	
PREFERRED ORIENTATION ANALYSIS IN TEXTURED MATERIALS	263
H. J. Bunge	
TEXTURE CHARACTERISATION IN X-RAY POWDER DIFFRACTION USING THE MARCH FORMULA	277
B. H. O'Connor, D. Y. Li and H. Sitepu	
TEXTURE ANALYSIS OF BULK SAMPLES BY NEUTRON DIFFRACTION USING A POSITION SENSITIVE DETECTOR	285
G. Will, E. Jansen and W. Schäfer	
POLE FIGURE AND ORIENTATION DISTRIBUTION FUNCTION ANALYSES OF FCC AND BCC METALS	293
C. Feng and F. Witt	
CORRECTING EFFECT OF PREFERRED ORIENTATION IN TRANSPARENT SAMPLES ..	303
M. Järvinen, M.-L. Laakkonen and T. Paakkari	
X-RAY TEXTURE MEASUREMENT USING A POSITION SENSITIVE DETECTOR	309
L. Wcislak, H. J. Bunge, M. Haase and C. Nauer-Gerhardt	
TEXTURE DEVELOPMENT IN POWDER MIXTURES	321
B. Gao, H. J. Bunge, C. J. Fantner, R. A. van der Veen	

VI. XRD INSTRUMENTATION, TECHNIQUES AND REFERENCE MATERIALS

OPPORTUNITIES FOR MATERIALS ANALYSIS WITH NEXT GENERATION SYNCHROTRON SOURCES	329
M. Hart	
XRD INSTRUMENT SENSITIVITY RESULTS FROM A ROUND ROBIN STUDY	333
W. N. Schreiner, R. Jenkins and P. F. Dismore	
INTRODUCTION OF A NIST INSTRUMENT SENSITIVITY STANDARD REFERENCE MATERIAL FOR X-RAY POWDER DIFFRACTION	341
J. P. Cline, S. B. Schiller and R. Jenkins	
POWDER DIFFRACTION DATA CORRECTION: SINGLE-CRYSTAL STANDARDS AND FOURIER ASYMMETRIC COMPONENT STRIPPING	353
F. E. Briden and R. B. Snoddy	
A LOW COST SECONDARY TWO THETA STANDARD FOR POWDER DIFFRACTOMETRY	359
D. J. Stabb	
CALIBRATING FOR X-RAY DIFFRACTION ANALYSIS OF TRACE QUARTZ	363
J. Renault, C. McKee and J. Barker	
CONSTRUCTION OF A MULTIMODE HIGH RESOLUTION X-RAY POWDER DIFFRACTOMETER AND ITS PERFORMANCE	375
M. Kurahashi, K. Honda, M. Goto, Y. Inari and C. Katayama	
2 θ / α SCAN X-RAY POWDER DIFFRACTOMETER	383
Y. Kobayashi	
CHEMICAL STATE ANALYSIS USING A GEARLESS TWO-CRYSTAL X-RAY SPECTROMETER	393
T. Konishi, K. Nishihagi and K. Taniguchi	
FOCUSING W K α 1 WITH A CURVED Si CRYSTAL	401
M. A. Short, M. R. Fallon, D. J. Nagel and C. M. Dozier	
APPLICATION OF IMAGING PLATE FOR X-RAY DIFFRACTOMETRY	407
A. Shibata, K. Sasaki and T. Kinefuchi	
TIME-RESOLVED OBSERVATIONS OF SOLID REACTIONS AND STRUCTURE TRANSITIONS USING A PSD, AN SSD AND COMPUTER AIDED MEASUREMENT AND CONTROL	415
T. Yamanaka, S. Kawasaki and T. Shibata	
EXPERIMENTAL CONSIDERATIONS AND LIMITATIONS IN THE APPLICATION OF ULTRA HIGH TEMPERATURE (2100°C) X-RAY DIFFRACTION	425
S. S. Iyengar	
ACCURATE DETERMINATION OF UNIT-CELL PARAMETERS USING CONVENTIONAL X-RAY POWDER DIFFRACTOMETRY	431
H. Toraya and W. Parrish	

VII. STRESS DETERMINATION BY DIFFRACTION METHODS

DETERMINING STRESSES IN COMPOSITES	439
J. B. Cohen	
RECENT DEVELOPMENTS IN STRESS ANALYSIS BY DIFFRACTION METHODS	449
V. Hauk	
DEFINING RESIDUAL STRESSES IN THIN FILM STRUCTURES	461
I. C. Noyan	
A COMPARISON OF X-RAY AND NEUTRON DIFFRACTION MEASUREMENT OF LATTICE PARAMETERS FOR THE DETERMINATION OF RESIDUAL STRESS AND CHEMICAL COMPOSITION IN ZIRCONIUM ALLOY TUBES	475
M. Griffiths, J. E. Winegar, J. F. Mecke, T. M. Holden and R. A. Holt	
FORMALISM FOR THE EVALUATION OF PSEUDO-MACRO STRESS FIELDS $\sigma_{33}(z)$ FROM Ω - AND ψ -MODE DIFFRACTION EXPERIMENTS PERFORMED WITH SYNCHROTRON RADIATION	481
H. Ruppersberg	
MATERIAL STRENGTH EVALUATION AND DAMAGE DETECTION BY X-RAY DIFFRACTION	489
T. Goto	
X-RAY STUDY ON THE FATIGUE FRACTURE SURFACE OF AUSTEMPERED DUCTILE CAST IRON	503
Y. Kishi, Y. Hirose, Z. Yajima and K. Tanaka	
THE STUDY OF FATIGUE BEHAVIOR OF DUCTILE CAST IRON BY MEANS OF X-RAY FRACTOGRAPHIC TECHNIQUE	511
Z. Yajima, M. Shinohara, K. Ishikawa, Y. Hirose and K. Tanaka	
DEPENDENCE OF STRESS CONSTANT ON MICROSTRUCTURE OF QUENCHED AND TEMPERED STEELS IN X-RAY STRESS MEASUREMENT	519
M. Kurita and A. Saito	
YOUNG'S MODULUS MEASUREMENT OF CHROMIUM ELECTROPLATING	527
M. Ohtsuka, H. Matsuoka, Y. Hirose and H. Ishii	
X-RAY ANALYSIS OF STRESS IN A LOCALIZED AREA BY USE OF IMAGING PLATE	537
Y. Yoshioka and S. Ohya	
THE APPLICATION OF X-RAY DIFFRACTION METHOD TO THE MEASUREMENT OF CRYSTAL DEFORMATION AND CRYSTAL MODULUS OF HIGH POLYMERS	545
K. Nakamae and T. Nishino	
A STUDY ON THE MISALIGNMENT OF A SOLLER-SLIT PACK IN A PARALLEL-BEAM GEOMETRY DIFFRACTOMETER	553
L. E. Depero, M. Zocchi and P. Bonzi	
ANALYSIS OF X-RAY DIFFRACTION DATA FOR THE CHARACTERIZATION OF RESIDUAL STRESS	561
J. S. Park and J. F. Shackelford	

VIII. XRD PROFILE FITTING, CRYSTALLITE SIZE AND STRAIN DETERMINATION

HFIT, A PROGRAM FOR INTERACTIVE ANALYSIS OF POWDER DIFFRACTION DATA	571
G. Will and Ch. Höffner	
PROFILE FITTING BY THE INTERFERENCE FUNCTION	577
L. Lutterotti and P. Scardi	
THE STRUCTURE OF NANOCRYSTALLINE IRON AND TUNGSTEN POWDERS PREPARED BY HIGH-ENERGY BALL MILLING	585
C. N. J. Wagner, E. Yang and M. S. Boldrick	
DETERMINATION OF DISLOCATION DENSITIES IN HEXAGONAL CLOSE-PACKED METALS USING X-RAY DIFFRACTION AND TRANSMISSION ELECTRON MICROSCOPY	593
M. Griffiths, J. E. Winegar, J. F. Mecke and R. A. Holt	
CHARACTERIZATION OF FERROELECTRIC PZT THIN FILMS - LINE BROADENING STUDY (USING GRAZING INCIDENCE GEOMETRY)	601
M. O. Eatough, R. P. Goehner, T. J. Headley and B. A. Tuttle	
AN X-RAY DIFFRACTION STUDY OF COMPACTED METAL POWDERS	607
P. D. Killen, N. A. Raftery and D. G. Hay	
NUMERICAL CALCULATION OF AXIAL DIVERGENCE PROFILES	611
R. A. Coyle	

IX. XRD APPLICATIONS: DETECTION LIMITS, SUPERCONDUCTORS, ORGANICS, MINERALS

X-RAY DIFFRACTION FROM A 28 ATTOLITER CRYSTAL VOLUME	617
E. F. Skelton, J. D. Ayers, S. B. Qadri, J. Z. Hu, L. W. Finger and H. K. Mao	
ANALYSIS OF $\text{YBa}_2\text{Cu}_3\text{O}_{7-x}$ PERITECTIC REACTIONS AND ORIENTATION BY HIGH TEMPERATURE XRD AND OPTICAL MICROSCOPY	623
R. L. Snyder, M. A. Rodriguez, B. J. Chen, D. P. Matheis, H. E. Göbel, G. Zorn and B. Seebacher	
OXIDATION/REDUCTION MELTING EQUILIBRIA IN THE SYSTEM $\text{BaO}-1/2\text{Y}_2\text{O}_3-\text{CuO}$, II. POWDER X-RAY ANALYSIS	633
W. Wong-Ng and L. P. Cook	
PROBING STRUCTURE-PROPERTY RELATIONSHIPS IN A FAMILY OF ARYLOXYPHENOXY PROPIONATE HERBICIDES USING SINGLE CRYSTAL X-RAY DIFFRACTION TECHNIQUES	641
P. R. Rudolf, L. Kershner and J. Tai	
SAXS MEASUREMENT OF MORPHOLOGY AND ITS RELATIONSHIP TO MELTING POINT DEPRESSION IN POLY(BETA-HYDROXYBUTYRATE-CO- BETA-HYDROXYVALERATE) RANDOM COPOLYMERS	645
T. L. Bluhm, W. J. Orts and R. H. Marchessault	
NEW DIRECTIONS IN THE X-RAY DIFFRACTION ANALYSIS OF ORGANIC MATERIALS	653
R. Jenkins	

THE ON-STREAM X-RAY ANALYSIS OF SLURRIES FOR PROCESS CONTROL	661
J. P. Engelbrecht, J. P. R. de Villiers and S. W. de Bruyn	
"WHOLE PATTERN" XRD INTERPRETATION OF MINERALOGICAL VARIATION	673
R. E. Ferrell, Jr., L. R. LaMotte, W. S. LeBlanc, D. E. Wilensky and L. Mao	
NONLINEAR EQUATIONS FOR HIGH ACCURACY X-RAY CRYSTAL ORIENTATION	681
D. Dragoi	
PHASE MICROIDENTIFICATION FROM SELECTED AREA ELECTRON DIFFRACTION (SAED) AND ENERGY DISPERSIVE SPECTROSCOPY (EDS) DATA	687
J. Macicek	